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1	IS&R	482	(375/267) .CCLS.	US-PGPUB; USPAT; EPO; DERWENT	2004/11/26 10:32				S1
2	IS&R	146	(375/143) .CCLS.	US-PGPUB; USPAT; EPO; DERWENT	2004/11/26 10:32				S2
3	IS&R	392	(375/298) .CCLS.	US-PGPUB; USPAT; EPO; DERWENT	2004/11/26 10:32				S3
4	IS&R	163	(375/299) .CCLS.	US-PGPUB; USPAT; EPO; DERWENT	2004/11/26 10:32				S4
5	IS&R	380	(455/101) .CCLS.	US-PGPUB; USPAT; EPO; DERWENT	2004/11/26 10:32				S5
6	BRS	0	S6 and S1	US-PGPUB; USPAT; EPO; DERWENT	2004/11/26 10:34				S7
7	BRS	0	S6 and S2	US-PGPUB; USPAT; EPO; DERWENT	2004/11/26 10:34				S8
8	BRS	1	S6 and S3	US-PGPUB; USPAT; EPO; DERWENT	2004/11/26 10:35				S9
9	BRS	0	S6 and S4	US-PGPUB; USPAT; EPO; DERWENT	2004/11/26 10:35				S10
10	BRS	21	detect\$3 same demodulat\$3 same complex same sequence same multiply\$3	US-PGPUB; USPAT; EPO; DERWENT	2004/11/26 10:53				S6
11	IS&R	1	("6243561") .PN.	US-PGPUB; USPAT	2004/11/26 10:53				S11



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diversity In: All Fields

And 

ake	In: All Fields	
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And 

average In: All Fields 

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diversity In: All Fields

And

demodulate In: All Fields

And

average In: All Fields

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diversity In: All Fields

And

multiply In: All Fields

And

average In: All Fields

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